Abstracts

An Efficient and Cost Effective SAW Device Measurement Method Based on an S-Parameter Estimation Technique

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Efficient and cost effective testing is an important part of the production process of SAW components. One aspect of testing is the measurement of the device transfer characteristic. In many cases expensive test fixtures containing matching networks are required. In order to reduce production costs and facilitate the measurement of transfer functions without matching networks, a different approach has been taken. Through use of estimation methods one can reduce the amount of information required to calculate a matched transfer function. Therefore, we developed a method by which a simulated match could be performed, but required only knowledge of the unmatched and uncalibrated S/sub 21/-parameter. The feasibility of our technique is demonstrated with a low loss IF SPUDT filter for mobile telephone applications.

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